

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

General Description

The MAX3000E/MAX3001E/MAX3002–MAX3012 8-channel level translators provide the level shifting necessary to allow data transfer in a multivoltage system. Externally applied voltages, VCC and VL, set the logic levels on either side of the device. Logic signals present on the VL side of the device appear as a higher voltage logic signal on the VCC side of the device, and vice-versa.

The MAX3000E/MAX3001E/MAX3002/MAX3003 use an architecture specifically designed to be bidirectional without the use of a directional pin.

The MAX3000E/MAX3001E/MAX3002/MAX3004–MAX3012 feature an EN input that, when low, reduces the $V_{\rm CC}$ and $V_{\rm L}$ supply currents to < 2 μ A. The MAX3000E/MAX3001E also have ±15kV ESD protection on the I/O $V_{\rm CC}$ side for greater protection in applications that route signals externally. The MAX3000E operates at a guaranteed data rate of 230kbps. The MAX3001E operates at a guaranteed data rate of 4Mbps. The MAX3002–MAX3012 operate at a guaranteed data rate of 20Mbps over the entire specified operating voltage range.

The MAX3000E/MAX3001E/MAX3002–MAX3012 accept V_L voltages from +1.2V to +5.5V and V_{CC} voltages from +1.65V to +5.5V, making them ideal for data transfer between low-voltage ASICs/PLDs and higher voltage systems. The MAX3000E/MAX3001E/MAX3002–MAX3012 are available in 20-bump UCSPTM, 20-pin TQFN (5mm x 5mm), and 20-pin TSSOP packages.

_Applications

CMOS Logic-Level Translation

Cellphones

SPI™ and MICROWIRE™ Level Translation

Low-Voltage ASIC Level Translation

Smart Card Readers

Cellphone Cradles

Portable POS Systems

Portable Communication Devices

Low-Cost Serial Interfaces

GPS

Telecommunications Equipment

UCSP is a trademark of Maxim Integrated Products, Inc. SPI is a trademark of Motorola, Inc.

MICROWIRE is a trademark of National Semiconductor.

Features

- Guaranteed Data Rate Options 230kbps (MAX3000E) 4Mbps (MAX3001E) 20Mbps (MAX3002–MAX3012)
- ♦ Bidirectional Level Translation Without Using a Directional Pin (MAX3000E/MAX3001E/MAX3002/ MAX3003)
- Unidirectional Level Translation (MAX3004–MAX3012)
- ♦ Operation Down to +1.2V on V_L
- ◆ ±15kV ESD Protection on I/O V_{CC} Lines (MAX3000E/MAX3001E)
- ♦ Ultra-Low 0.1µA Supply Current in Shutdown
- ♦ Low Quiescent Current (< 10µA)
- ♦ UCSP, TQFN, and TSSOP Packages

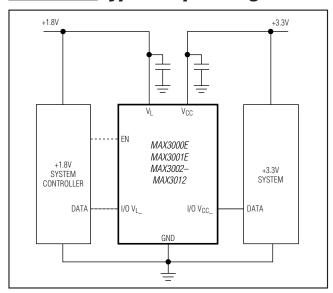
Ordering Information

PART	TEMP RANGE	PIN-PACKAGE
MAX3000EEUP	-40°C to +85°C	20 TSSOP
MAX3000EEBP-T	-40°C to +85°C	4 x 5 UCSP

Ordering Information continued at end of data sheet.

Note: All devices operate over the -40°C to +85°C operating temperature range.

Typical Operating Circuit



Pin Configurations and Functional Diagrams appear at end of data sheet.

For pricing, delivery, and ordering information, please contact Maxim Direct at 1-888-629-4642, or visit Maxim's website at www.maximintegrated.com.

19-2672; Rev 5; 8/08

$\pm 1.2V$ to $\pm 5.5V$, $\pm 15kV$ ESD-Protected, $0.1\mu A$, 35Mbps, 8-Channel Level Translators

ABSOLUTE MAXIMUM RATINGS

(All voltages referenced to GND.)
V _C C0.3V to +6V
-0.3V to +6V
I/O V _{CC}
$I/O V_L$ 0.3V to $(V_L + 0.3V)$
EN, EN A/B0.3V to +6V
Short-Circuit Duration I/O VL , I/O VCC to GNDContinuous
Continuous Power Dissipation ($T_A = +70^{\circ}$ C)
20-Pin TSSOP (derate 7.0mW/°C above +70°C)559mW
20-Bump UCSP (derate 10mW/°C above +70°C)800mW
20-Pin 5mm x 5mm TQFN
(derate 20.0mW/°C above +70°C)

Operating Temperature Ranges	
MAX3001EAUP	40°C to +125°C
MAX300_EE_P	40°C to +85°C
MAX30E_P	40°C to +85°C
Junction Temperature	+150°C
Storage Temperature Range	65°C to +150°C
Lead Temperature (soldering, 10s)	+300°C

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ELECTRICAL CHARACTERISTICS

 $(V_{CC} = +1.65 V \text{ to } +5.5 V, \ V_L = +1.2 V \text{ to } V_{CC}, \ EN = V_L \ (MAX3000 E/MAX3001 E/MAX3002/MAX3004 - MAX3012), \ EN \ A/B = V_L \ or \ O(MAX3003), \ T_A = T_{MIN} \ to \ T_{MAX}. \ Typical values are at \ V_{CC} = +1.65 V, \ V_L = +1.2 V, \ and \ T_A = +25 °C.) \ (Notes 1, 2)$

PARAMETER	SYMBOL	OL CONDITIONS		TYP	MAX	UNITS	
POWER SUPPLIES							
V _L Supply Range	VL		1.2		Vcc	V	
V _{CC} Supply Range	Vcc		1.65		5.50	V	
Supply Current from V _{CC}	lovoo	I/O V _{CC} _= 0, I/O V _L _= 0 or I/O V _{CC} _= V _{CC} , I/O V _L _= V _L , MAX3000E/MAX3002–MAX3012		0.1	10	шЛ	
Supply Current Horn VCC	lavcc	$I/O V_{CC_{-}} = 0$, $I/O V_{L_{-}} = 0$ or $I/O V_{CC_{-}} = V_{CC}$, $I/O V_{L_{-}} = V_{L}$, MAX3001E		0.1	50	- μΑ	
Supply Current from V	lQVL	I/O V _{CC} _= 0, I/O V _L _= 0 or I/O V _{CC} _= V _{CC} , I/O V _L _= V _L , MAX3000E/MAX3002–MAX3012		0.1	10		
Supply Current from V _L		I/O V _{CC} _= 0, I/O V _L _= 0 or I/O V _{CC} _= V _{CC} , I/O V _L _= V _L , MAX3001E		0.1	50	μΑ	
V _{CC} Shutdown Supply Current	Ishdn-vcc	T _A = +25°C, EN = 0, MAX3000E/MAX3001E/MAX3002/ MAX3004–MAX3012		0.1	2	μА	
		T _A = +25°C, EN A/B = 0, MAX3003		0.1	2		
V _L Shutdown Supply Current	ISHDN-VL	T _A = +25°C, EN = 0, MAX3000E/MAX3001E/MAX3002/ MAX3004–MAX3012		0.1	2	μΑ	
		T _A = +25°C, EN A/B = 0, MAX3003		0.1	2		

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ELECTRICAL CHARACTERISTICS (continued)

 $(V_{CC} = +1.65 V \ to \ +5.5 V, \ V_{L} = +1.2 V \ to \ V_{CC}, \ EN = V_{L} \ (MAX3000 E/MAX3001 E/MAX3002/MAX3004 - MAX3012), \ EN \ A/B = V_{L} \ or \ 0 \ (MAX3003), \ T_{A} = T_{MIN} \ to \ T_{MAX}. \ Typical \ values \ are \ at \ V_{CC} = +1.65 V, \ V_{L} = +1.2 V, \ and \ T_{A} = +25 ^{\circ}C.) \ (Notes \ 1, \ 2)$

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
I/O V _{CC} _ Three-State Output Leakage Current		T _A = +25°C, EN = 0, MAX3000E/MAX3001E/MAX3002/ MAX3004–MAX3012		0.1	2	μA
Leakage Cullelli		T _A = +25°C, EN A/B = 0, MAX3003		0.1	2	
I/O V _L _Three-State Output Leakage Current		EN A/B = 0, MAX3003		0.1	2	μΑ
I/O V _L Pulldown Resistance During Shutdown		EN = 0, MAX3000E/MAX3001E/MAX3002/ MAX3004–MAX3012	4.59		8.30	kΩ
EN or EN A/B Input Leakage Current		T _A = +25°C			1	μΑ
LOGIC-LEVEL THRESHOLDS						
I/O V _L _Input-Voltage High Threshold	VIHL				2/3 x V _L	V
I/O V _L Input-Voltage Low Threshold	VILL		1/3 x V _L			V
I/O V _{CC} _Input-Voltage High Threshold	VIHC				2/3 x V _{CC}	V
I/O V _{CC} _Input-Voltage Low Threshold	V _{ILC}		1/3 x V _{CC}			V
EN, EN A/B Input-Voltage High Threshold	VIH				V _L - 0.4	V
EN, EN A/B Input-Voltage Low Threshold	VIL		0.4			V
I/O V _L _ Output-Voltage High	Vohl	I/O V _L source current = 20µA, I/O V _{CC} ≥ V _{CC} - 0.4V	V _L - 0.4			V
I/O V _L Output-Voltage Low	Voll	I/O V _L sink current = 20μ A, I/O V _{CC} ≤ 0.4 V			0.4	V
I/O V _{CC} _ Output-Voltage High	Vohc	I/O V _{CC} _source current = 20µA, I/O V _L _≥ V _L - 0.4V	V _C C - 0.4			V
I/O V _{CC} _ Output-Voltage Low	Volc	I/O V _{CC} sink current = 20µA, I/O V _L ≤ 0.4V			0.4	V
ESD PROTECTION						
I/O V _{CC} _		Human Body Model, MAX3000E/MAX3001E		±15		kV

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TIMING CHARACTERISTICS

 $(V_{CC}=+1.65V\ to\ +5.5V,\ V_L=+1.2V\ to\ V_{CC},\ EN=V_L\ (MAX3000E/MAX3001E/MAX3002/MAX3004-MAX3012),\ EN\ A/B=V_L\ or\ 0\ (MAX3003),\ T_A=T_{MIN}\ to\ T_{MAX}.\ Typical\ values\ are\ at\ V_{CC}=+1.65V,\ V_L=+1.2V,\ and\ T_A=+25^\circC.)\ (Notes\ 1,\ 2)$

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	
		$R_S = 50\Omega$, $C_{VCC} = 50$ pF, MAX3000E, Figures 1a, 1b	400	800	1200		
I/O V _{CC} _ Rise Time	tRVCC	$R_S = 50\Omega$, $C_{VCC} = 50$ pF, MAX3001E, Figures 1a, 1b		25	50	ns	
		$R_S = 50\Omega$, $C_{VCC} = 50$ pF, MAX3002–MAX3012, Figures 1a, 1b			15		
		$R_S = 50\Omega$, $C_{VCC} = 50$ pF, MAX3000E, Figures 1a, 1b	400	800	1200		
I/O V _{CC} _ Fall Time	tFVCC	$R_S = 50\Omega$, $C_{VCC} = 50$ pF, MAX3001E, Figures 1a, 1b		25	50	ns	
		$R_S = 50\Omega$, $C_{VCC} = 50$ pF, MAX3002–MAX3012, Figures 1a, 1b			15		
		$R_S = 50\Omega$, $C_{VL} = 50$ pF, MAX3000E, Figures 2a, 2b	400	800	1200		
I/O V _{L_} Rise Time	t _{RVL}	$R_S = 50\Omega$, $C_{VL} = 50$ pF, MAX3001E, Figures 2a, 2b		25	50	ns	
		$R_S = 50\Omega$, $C_{VL} = 15pF$, MAX3002–MAX3012, Figures 2a, 2b			15		
		$R_S = 50\Omega$, $C_{VL} = 50$ pF, MAX3000E, Figures 2a, 2b	400	800	1200		
I/O V _L _Fall Time	t _{FVL}	$R_S = 50\Omega$, $C_{VL} = 50$ pF, MAX3001E, Figures 2a, 2b		25	65	ns	
		$R_S = 50\Omega$, $C_{VL} = 15pF$, MAX3002–MAX3012, Figures 2a, 2b			15		
		$R_S = 50\Omega$, $C_{VCC} = 50$ pF, MAX3000E, Figures 1a, 1b			1000		
Propagation Delay (Driving I/O VL_)	I/O _{VL-VCC}	$R_S = 50\Omega$, $C_{VCC} = 50$ pF, MAX3001E, Figures 1a, 1b			50	ns	
		R _S = 50Ω, C _{VCC} = 50pF, MAX3002–MAX3012, Figures 1a, 1b			20		
		$R_S = 50\Omega$, $C_{VL} = 50$ pF, MAX3000E, Figures 2a, 2b			1000		
Propagation Delay (Driving I/O V _{CC} _)	I/Ovcc-vl	$R_S = 50\Omega$, $C_{VL} = 50$ pF, MAX3001E, Figures 2a, 2b			50	ns	
		$R_S = 50\Omega$, $C_{VL} = 15pF$, MAX3002–MAX3012, Figures 2a, 2b			20		

Note 1: All units are 100% production tested at $T_A = +25$ °C. Limits over the operating temperature range are guaranteed by design and not production tested.

Note 2: For normal operation, ensure that V_L < V_{CC}. During power-up, V_L > V_{CC} does not damage the device.

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

TIMING CHARACTERISTICS (continued)

 $(V_{CC} = +1.65 V \text{ to } +5.5 V, \ V_L = +1.2 V \text{ to } V_{CC}, \ EN = V_L \ (MAX3000 E/MAX3001 E/MAX3002/MAX3004 - MAX3012), \ EN \ A/B = V_L \ or \ 0 \ (MAX3003), \ T_A = T_{MIN} \ to \ T_{MAX}. \ Typical values are at \ V_{CC} = +1.65 V, \ V_L = +1.2 V, \ and \ T_A = +25 °C.) \ (Notes \ 1, \ 2)$

PARAMETER	R SYMBOL CONDITIONS		MIN	TYP	MAX	UNITS	
		$R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 50$ pF, MAX3000E	50/		500		
Channel-to-Channel Skew	tskew	$R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 50$ pF, MAX3001E			10	ns	
		$R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 15$ pF, MAX3002–MAX3012			5		
		$R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 50$ pF, $\Delta T_A = +20$ °C, MAX3000E (Note 3)			800		
Part-to-Part Skew	tppskew	$R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 50$ pF, $\Delta T_A = +20$ °C, MAX3001E (Note 3)			30	ns	
		$R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 15$ pF, $\Delta T_A = +20$ °C, MAX3002–MAX3012 (Note 3)			10		
Propagation Delay from I/O V _L to I/O V _{CC} after EN	tEN-VCC	C _{VCC} = 50pF, MAX3000E/MAX3001E, MAX3002–MAX3012, Figure 3			2	μs	
Propagation Delay from I/O V _{CC} to I/O V _L after EN	t _{EN-VL}	C _{VL} = 50pF, MAX3000E/MAX3001E/ MAX3002/MAX3004–MAX3012, Figure 4			2	μs	
I/O VCC_ to I/O VC_ after EIV		C _{VL} = 15pF, MAX3003, Figure 4	2		1		
		$R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 50$ pF, MAX3000E	230			kbps	
Maximum Data Rate		$R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 50$ pF, MAX3001E	4			Mhna	
		$R_S = 50\Omega$, $C_{VCC} = 50$ pF, $C_{VL} = 15$ pF, MAX3002–MAX3012	20			Mbps	

Note 3: VCC from device 1 must equal VCC of device 2; VL from device 1 must equal VL of device 2.

+1.2V to +5.5V, $\pm15kV$ ESD-Protected, $0.1\mu A$, 35Mbps, 8-Channel Level Translators

TIMING CHARACTERISTICS—MAX3002-MAX3012

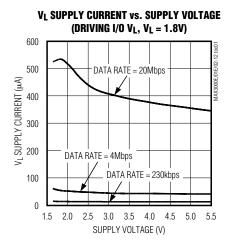
 $(V_{CC} = +1.65V \text{ to } +5.5V, V_L = +1.2V \text{ to } V_{CC}, EN = V_L \text{ (MAX3002/MAX3004-MAX3012)}, EN A/B = V_L \text{ or 0 (MAX3003)}, T_A = T_{MIN} \text{ to } T_{MAX.})$ (Notes 1, 2)

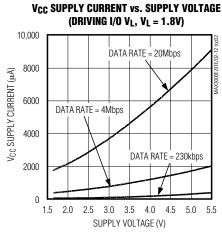
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	
$+1.2V \le V_L \le V_{CC} \le +3.3V$	•		<u>.</u>				
I/O V _{CC} _ Rise Time	t _{RVCC}				15	ns	
I/O V _{CC} _ Fall Time	tFVCC				15	ns	
I/O V _L _ Rise Time	t _{RVL}				15	ns	
I/O V _L _ Fall Time	t _{FVL}				15	ns	
Propagation Delay	I/O _{VL-VCC}	Driving I/O V _L _			15	no	
Propagation Delay	I/Ovcc-vl	Driving I/O V _{CC} _			15	ns	
Channel-to-Channel Skew	tskew	Each translator equally loaded			5	ns	
Maximum Data Rate			20			Mbps	
+2.5V ≤ V _L ≤ V _{CC} ≤ +3.3V							
I/O V _{CC} _ Rise Time	tRVCC				8.5	ns	
I/O V _{CC} _ Fall Time	tFVCC				8.5	ns	
I/O V _L _ Rise Time	t _{RVL}				8.5	ns	
I/O V _L _ Fall Time	t _{FVL}				8.5	ns	
Drangation Daloy	I/O _{VL-VCC}	Driving I/O V _L _			8.5	no	
Propagation Delay	I/O _{VCC-VL}	Driving I/O V _{CC} _			8.5	ns	
Channel-to-Channel Skew	tskew	Each translator equally loaded			10	ns	
Maximum Data Rate			35			Mbps	
$\textbf{+1.8V} \leq \textbf{V}_{\textbf{L}} \leq \textbf{V}_{\textbf{CC}} \leq \textbf{+2.5V}$							
I/O V _{CC} _ Rise Time	tRVCC				10	ns	
I/O V _{CC} _ Fall Time	tFVCC				10	ns	
I/O V _{L_} Rise Time	t _{RVL}				10	ns	
I/O V _L _ Fall Time	t _{FVL}				10	ns	
Propagation Dolay	I/O _{VL-VCC}	Driving I/O V _L _			15		
Propagation Delay	I/O _{VCC-VL}	Driving I/O V _{CC} _			10	ns	
Channel-to-Channel Skew	tskew	Each translator equally loaded			5	ns	
Maximum Data Rate			30			Mbps	

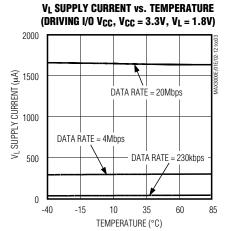
+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Typical Operating Characteristics

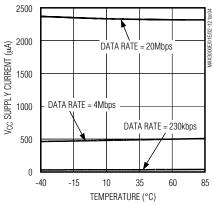
 $(T_A = +25^{\circ}C, \text{ unless otherwise noted.})$



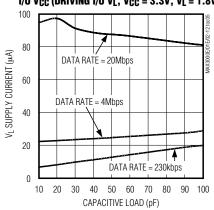




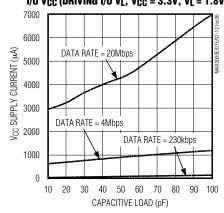
 V_{CC} SUPPLY CURRENT vs. TEMPERATURE (DRIVING I/O V_{CC} , V_{CC} = 3.3V, V_L = 1.8V)



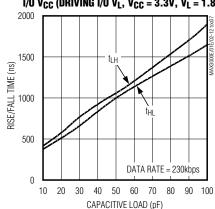
 V_L SUPPLY CURRENT vs. CAPACITIVE LOAD ON I/O V_{CC} (DRIVING I/O V_L , V_{CC} = 3.3V, V_L = 1.8V)



V_{CC} SUPPLY CURRENT vs. CAPACITIVE LOAD ON I/O V_{CC} (DRIVING I/O V_L, V_{CC} = 3.3V, V_L = 1.8V)



 $\label{eq:max3000e} \begin{array}{c} \text{Max3000e} \\ \text{Rise/fall time vs. Capacitive load on} \\ \text{I/O V}_{CC} \ (\text{Driving I/O V}_L, \, \text{V}_{CC} = 3.3\text{V}, \, \text{V}_L = 1.8\text{V}) \end{array}$

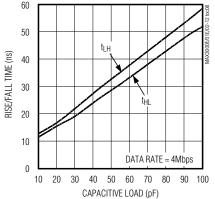


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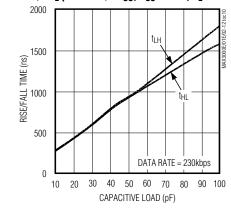
Typical Operating Characteristics (continued)

 $(T_A = +25^{\circ}C, \text{ unless otherwise noted.})$

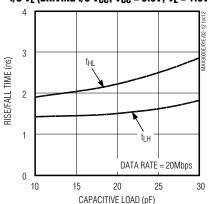
 $\label{eq:max3001E} \begin{array}{c} \text{Max3001E} \\ \text{Rise/fall time vs. Capacitive load on} \\ \text{I/O V}_{CC} \ (\text{Driving I/O V}_L, \ \text{V}_{CC} = 3.3V, \ \text{V}_L = 1.8V) \end{array}$



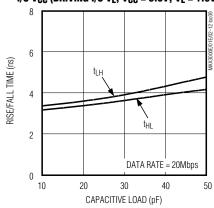
MAX3UUUE
RISE/FALL TIME vs. CAPACITIVE LOAD ON $I/O V_L (DRIVING I/O V_{CC}, V_{CC} = 3.3V, V_L = 1.8V)$



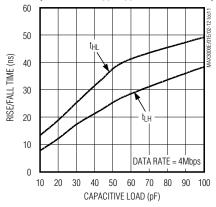
 $\label{eq:max3002-max3012} \begin{aligned} &\text{Max3002-max3012} \\ &\text{Rise/Fall Time vs. Capacitive load on} \\ &\text{I/O VL (Driving I/O VCC, VCC = 3.3V, VL = 1.8V)} \end{aligned}$



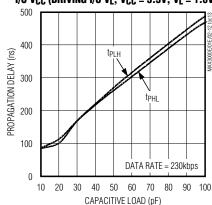
 $\label{eq:max3002-max3012} \begin{aligned} &\text{Max3002-max3012} \\ &\text{Rise/fall time vs. Capacitive load on} \\ &\text{I/O V}_{CC} \left(\text{Driving I/O V}_{L}, \text{V}_{CC} = 3.3\text{V}, \text{V}_{L} = 1.8\text{V} \right) \end{aligned}$



 $\begin{array}{c} \text{MAX3001E} \\ \text{RISE/FALL TIME vs. CAPACITIVE LOAD ON} \\ \text{I/O V}_L \text{ (DRIVING I/O V}_{CC}, \text{ V}_{CC} = 3.3\text{V}, \text{ V}_L = 1.8\text{V}) \end{array}$



 $\label{eq:max3000E} MAX3000E \\ PROPAGATION DELAY vs. CAPACITIVE LOAD ON \\ I/O \ V_{CC} \ (DRIVING I/O \ V_L, \ V_{CC} = 3.3V, \ V_L = 1.8V) \\$

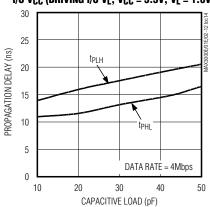


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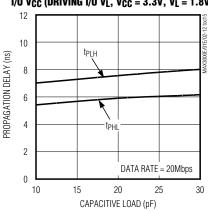
Typical Operating Characteristics (continued)

 $(T_A = +25^{\circ}C, \text{ unless otherwise noted.})$

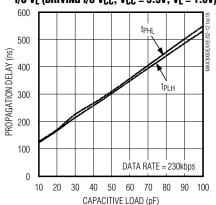
 $\label{eq:max3001E} \begin{array}{l} \text{MAX3001E} \\ \text{PROPAGATION DELAY vs. CAPACITIVE LOAD ON} \\ \text{I/O V}_{CC} \left(\text{DRIVING I/O V}_L, \text{V}_{CC} = 3.3\text{V}, \text{V}_L = 1.8\text{V} \right) \end{array}$



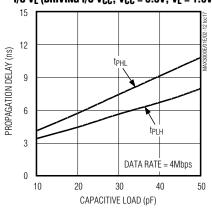
MAX3002-MAX3012
PROPAGATION DELAY vs. CAPACITIVE LOAD ON I/O VCC (DRIVING I/O VL. VCC = 3.3V, VL = 1.8V)



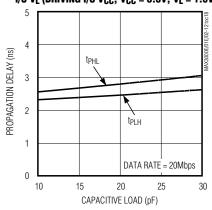
MAX3000E
PROPAGATION DELAY vs. CAPACITIVE LOAD ON I/O VL (DRIVING I/O VCC, VCC = 3.3V, VL = 1.8V)



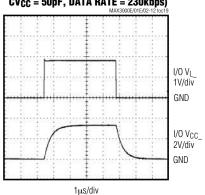
 $\begin{array}{c} MAX3001E \\ PROPAGATION DELAY vs. CAPACITIVE LOAD ON \\ I/O VL (DRIVING I/O V_{CC}, V_{CC} = 3.3V, V_L = 1.8V) \end{array}$



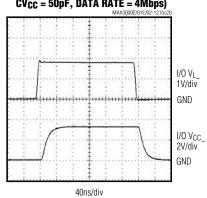
 $\label{eq:max3002-max3012} MAX3002-MAX3012 $$PROPAGATION DELAY vs. CAPACITIVE LOAD ON $$I/O V_L (DRIVING I/O V_{CC}, V_{CC} = 3.3V, V_L = 1.8V) $$$

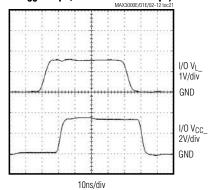


MAX3000E RAIL-TO-RAIL DRIVING (DRIVING I/O VL, $V_{CC} = 3.3V$, $V_L = 1.8V$, $CV_{CC} = 50pF$, DATA RATE = 230kbps)



MAX3001E RAIL-TO-RAIL DRIVING (DRIVING I/O V_L , $V_{CC} = 3.3V$, $V_L = 1.8V$, $CV_{CC} = 50pF$, data rate = 4Mbps)





+1.2V to +5.5V, ±15kV ESD-Protected, 0.1µA, 35Mbps, 8-Channel Level Translators

_____Pin Description

MAX3000E/MAX3001E/MAX3002

PIN		PIN		EUNICTION		
TSSOP	UCSP	TQFN	NAME	FUNCTION		
1	B1	19	I/O V _L 1	Input/Output 1, Referenced to V _L		
2	A1	20	VL	Logic Input Voltage, $+1.2V \le V_L \le V_{CC}$. Bypass V_L to GND with a $0.1\mu F$ capacitor.		
3	A2	1	I/O VL2	Input/Output 2, Referenced to V _L		
4	B2	2	I/O VL3	Input/Output 3, Referenced to V _L		
5	А3	3	I/O V _L 4	Input/Output 4, Referenced to V _L		
6	В3	4	I/O V _L 5	Input/Output 5, Referenced to V _L		
7	A4	5	I/O V _L 6	Input/Output 6, Referenced to V _L		
8	В4	6	I/O V _L 7	Input/Output 7, Referenced to VL		
9	A5	7	I/O VL8	Input/Output 8, Referenced to V _L		
10	B5	8	EN	Enable Input. If EN is pulled low, I/O $V_{CC}1$ to I/O $V_{CC}8$ are in three-state, while I/O $V_{L}1$ to I/O $V_{L}8$ have internal $6k\Omega$ pulldown resistors. Drive EN high (V_{L}) for normal operation.		
11	C5	9	GND	Ground		
12	D5	10	I/O V _{CC} 8	Input/Output 8, Referenced to V _{CC}		
13	C4	11	I/O V _{CC} 7	Input/Output 7, Referenced to V _{CC}		
14	D4	12	I/O V _{CC} 6	Input/Output 6, Referenced to V _{CC}		
15	C3	13	I/O V _{CC} 5	Input/Output 5, Referenced to VCC		
16	D3	14	I/O V _{CC} 4	Input/Output 4, Referenced to V _{CC}		
17	C2	15	I/O V _{CC} 3	Input/Output 3, Referenced to V _{CC}		
18	D2	16	I/O V _{CC} 2	Input/Output 2, Referenced to VCC		
19	D1	17	Vcc	V _{CC} Input Voltage, +1.65V ≤ V _{CC} ≤ +5.5V. Bypass V _{CC} to GND with a $0.1\mu F$ capacitor.		
20	C1	18	I/O V _{CC} 1	Input/Output 1, Referenced to VCC		
_	_	EP	EP	Exposed Pad. Connect to GND.		

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1µA, 35Mbps, 8-Channel Level Translators

Pin Description (continued)

MAX3003

PIN		PIN		FUNCTION		
TSSOP	UCSP	TQFN	NAME	FUNCTION		
1	B1	19	I/O V _L 1A	Input/Output 1A, Referenced to V _L		
2	A1	20	VL	Logic Input Voltage, $+1.2V \le V_L \le V_{CC}$. Bypass V_L to GND with a $0.1\mu F$ capacitor.		
3	A2	1	I/O VL2A	Input/Output 2A, Referenced to V _L		
4	B2	2	I/O VL3A	Input/Output 3A, Referenced to V _L		
5	А3	3	I/O VL4A	Input/Output 4A, Referenced to V _L		
6	В3	4	I/O V _L 1B	Input/Output 1B, Referenced to V _L		
7	A4	5	I/O V _L 2B	Input/Output 2B, Referenced to V _L		
8	B4	6	I/O VL3B	Input/Output 3B, Referenced to V _L		
9	A5	7	I/O VL4B	Input/Output 4B, Referenced to V _L		
10	B5	8	EN A/B	Enable Input. If EN A/B is pulled low, channels 1B through 4B are active, and channels 1A through 4A are in three-state. If EN A/B is driven high to V_L , channels 1A through 4A are active, and channels 1B through 4B are in three-state.		
11	C5	9	GND	Ground		
12	D5	10	I/O V _{CC} 4B	Input/Output 4B, Referenced to V _{CC}		
13	C4	11	I/O V _{CC} 3B	Input/Output 3B, Referenced to V _{CC}		
14	D4	12	I/O V _{CC} 2B	Input/Output 2B, Referenced to V _{CC}		
15	C3	13	I/O V _{CC} 1B	Input/Output 1B, Referenced to V _{CC}		
16	D3	14	I/O V _{CC} 4A	Input/Output 4A, Referenced to V _{CC}		
17	C2	15	I/O V _{CC} 3A	Input/Output 3A, Referenced to V _{CC}		
18	D2	16	I/O V _{CC} 2A	Input/Output 2A, Referenced to V _{CC}		
19	D1	17	Vcc	V _{CC} Input Voltage, +1.65V ≤ V _{CC} ≤ +5.5V. Bypass V _{CC} to GND with a 0.1μF capacitor.		
20	C1	18	I/O V _{CC} 1A	Input/Output 1A, Referenced to V _{CC}		
_	_	EP	EP	Exposed Pad. Connect to GND.		

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Pin Description (continued)

MAX3004-MAX3012

NAME	FUNCTION (Note 1)
Vcc	V _{CC} Input Voltage, +1.65V < V _{CC} < +5.5V. Bypass V _{CC} to GND with a 0.1μF capacitor.
VL	Logic Input Voltage, $+1.2V \le V_L \le V_{CC}$. Bypass V_L to GND with a $0.1\mu F$ capacitor.
GND	Ground
EN (MAX3004)	Enable Input. If EN is pulled low, OV _{CC} 1–OV _{CC} 8 are in three-state, while IV _L 1–IV _L 8 have $6k\Omega$ pulldown resistors. Drive EN high (V _L) for normal operation.
EN (MAX3005)	Enable Input. If EN is pulled low, IV $_{CC}$ 1 and OV $_{CC}$ 2-OV $_{CC}$ 8 are in three-state, while OV $_{L}$ 1 and IV $_{L}$ 2-IV $_{L}$ 8 have 6k $_{\Omega}$ pulldown resistors. Drive EN high (V $_{L}$) for normal operation.
EN (MAX3006)	Enable Input. If EN is pulled low, IV _{CC} 1, IV _{CC} 2, and OV _{CC} 3–OV _{CC} 8 are in three-state, while OV _L 1, OV _L 2, and IV _L 3–IV _L 8 have $6k\Omega$ pulldown resistors. Drive EN high (V _L) for normal operation.
EN (MAX3007)	Enable Input. If EN is pulled low, IV _{CC} 1, IV _{CC} 2, IV _{CC} 3, and OV _{CC} 4–OV _{CC} 8 are in three-state, while OV _L 1, OV _L 2, OV _L 3, and IV _L 4–IV _L 8 have $6k\Omega$ pulldown resistors. Drive EN high (V _L) for normal operation.
EN (MAX3008)	Enable Input. If EN is pulled low, IVCC1–IVCC4 and OVCC5–OVCC8 are in three-state, while OVL1–OVL4 and IVL5–IVL8 have $6k\Omega$ pulldown resistors. Drive EN high (VL) for normal operation.
EN (MAX3009)	Enable Input. If EN is pulled low, IV _{CC} 1–IV _{CC} 5, OV _{CC} 6, OV _{CC} 7, and OV _{CC} 8 are in three-state, while OV _L 1–OV _L 5, IV _L 6, IV _L 7, and IV _L 8 have $6k\Omega$ pulldown resistors. Drive EN high (V _L) for normal operation.
EN (MAX3010)	Enable Input. If EN is pulled low, IVCC1–IVCC6, OVCC7, and OVCC8 are in three-state, while OVL1–OVL6, IVL7, and IVL8 have $6k\Omega$ pulldown resistors. Drive EN high (VL) for normal operation.
EN (MAX3011)	Enable Input. If EN is pulled low, IVCC1-IVCC7 and OVCC8 are in three-state, while OVL1-OVL7 and IVL8 have $6k\Omega$ pulldown resistors. Drive EN high (VL) for normal operation.
EN (MAX3012)	Enable Input. If EN is pulled low, IVCC1–IVCC8 are in three-state, while OVL1–OVL8 have $6k\Omega$ pulldown resistors. Drive EN high (VL) for normal operation.
IVL1-IVL8	Inputs Referenced to V _L , Numbers 1 to 8
OV _L 1–OV _L 8	Outputs Referenced to V _L , Numbers 1 to 8
IV _{CC} 1-IV _{CC} 8	Inputs Referenced to V _{CC} , Numbers 1 to 8
OV _{CC} 1-OV _{CC} 8	Outputs Referenced to V _{CC} , Numbers 1 to 8

Note 1: For specific pin numbers, see the Pin Configurations.

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Test Circuits/Timing Diagrams

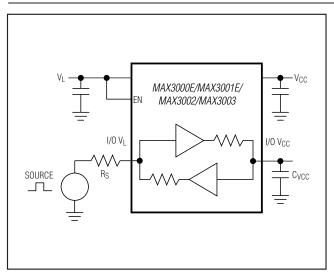


Figure 1a. Driving I/O VL

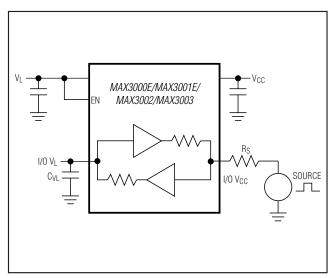


Figure 2a. Driving I/O VCC

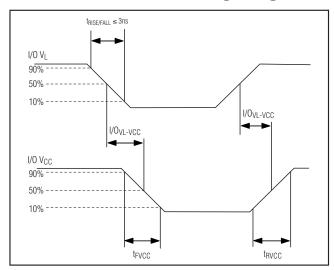


Figure 1b. Timing for Driving I/O VL

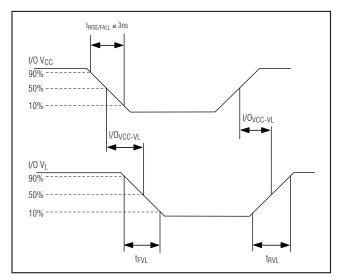


Figure 2b. Timing for Driving I/O VCC

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Test Circuits/Timing Diagrams (continued)

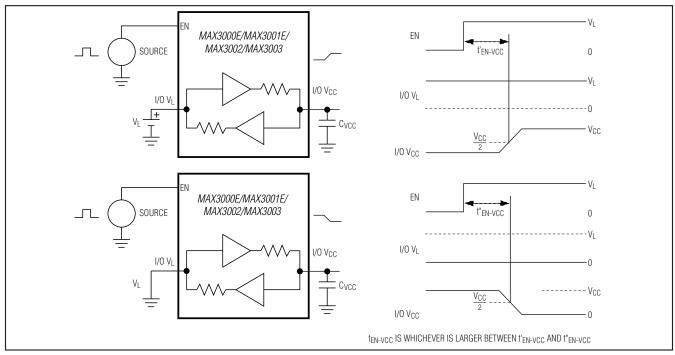


Figure 3. Propagation Delay from I/O V_L to I/O V_{CC} After EN

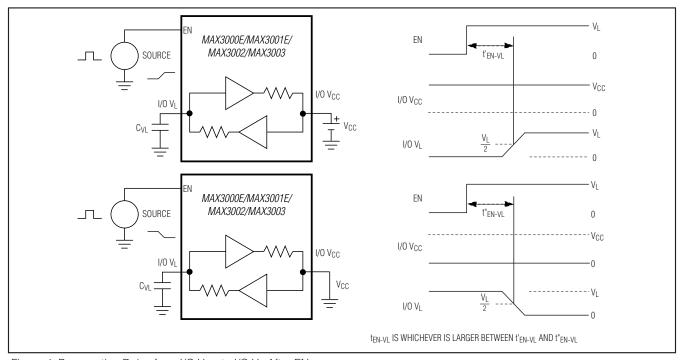


Figure 4. Propagation Delay from I/O V_{CC} to I/O V_L After EN

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Detailed Description

The MAX3000E/MAX3001E/MAX3002-MAX3012 logiclevel translators provide the level shifting necessary to allow data transfer in a multivoltage system. Externally applied voltages, VCC and VL, set the logic levels on either side of the device. Logic signals present on the V_I side of the device appear as a higher voltage logic signal on the Vcc side of the device, and vice-versa. The MAX3000E/MAX3001E/MAX3002/MAX3003 are bidirectional level translators allowing data translation in either direction (V_L ↔ V_{CC}) on any single data line. These devices use an architecture specifically designed to be bidirectional without the use of a direction pin. The MAX3004-MAX3012 unidirectional level translators level shift data in one direction (VL -> VCC or $V_{CC} \rightarrow V_{L}$) on any single data line. The MAX3000E/MAX3001E/ MAX3002-MAX3012 accept VL from +1.2V to +5.5V. All devices have VCC ranging from +1.65V to +5.5V, making them ideal for data transfer between low-voltage ASICs/PLDs and higher voltage systems.

The MAX3000E/MAX3001E/MAX3002/MAX3004—MAX3012 feature an output enable mode that reduces VCC supply current to less than $2\mu A$, and VL supply current to less than $2\mu A$ when in shutdown. The MAX3000E/MAX3001E have $\pm 15 kV$ ESD protection on the VCC side for greater protection in applications that route signals externally. The MAX3000E operates at a guaranteed data rate of 230kbps; the MAX3001E operates at a guaranteed data rate of 4Mbps and the MAX3002–MAX3012 are guaranteed with a data rate of 20Mbps of operation over the entire specified operating voltage range.

Level Translation

For proper operation, ensure that $+1.65V \le V_{CC} \le +5.5V$, $+1.2V \le V_L \le +5.5V$, and $V_L \le V_{CC}$. During power-up sequencing, $V_L \ge V_{CC}$ does not damage the device. During power-supply sequencing, when V_{CC} is floating and V_L is powering up, up to 10mA current can be sourced to each load on the V_L side, yet the device does not latch up.

The maximum data rate also depends heavily on the load capacitance (see the *Typical Operating Characteristics*), output impedance of the driver, and the operational voltage range (see the *Timing Characteristics* table).

Input Driver Requirements

The MAX3001E/MAX3002–MAX3012 architecture is based on a one-shot accelerator output stage. See Figure 5. Accelerator output stages are always in three-

state except when there is a transition on any of the translators on the input side, either I/O V_L or I/O V_{CC} .

When there is such a transition, the accelerator stages become active, charging (discharging) the capacitances at the I/Os. Due to its bidirectional nature, both stages become active during the one-shot pulse. This can lead to some current feeding into the external source that is driving the translator. However, this behavior helps to speed up the transition on the driven side.

For proper full-speed operation, the output current of a device that drives the inputs of the MAX3000E/MAX3001E/MAX3002–MAX3012 should meet the following requirements:

- MAX3000E (230kbps):
 i > 1mA, R_{drv} < 1kΩ
- MAX3001E (4Mbps):
 i > 10⁷ x V x (C + 10pF)
- MAX3002–MAX3012 (20Mbps):
 i > 10⁸ x V x (C + 10pF)

where i is the driver output current, V is the logic-supply voltage (i.e., V_L or V_{CC}) and C is the parasitic capacitance of the signal line.

Enable Output Mode (EN, EN A/B)

The MAX300E/MAX3001E/MAX3002 and the MAX3004–MAX3012 feature an EN input, and the MAX3003 has an EN A/B input. Pull EN low to set the MAX3000E/MAX3001E/MAX3002/MAX3004–MAX3012s' I/O VCC1 through I/O VCC8 in three-state output mode, while I/O VL1 through I/O VL8 have internal $6k\Omega$ pulldown resistors. Drive EN to logic-high (VL) for normal operation. The MAX3003 is intended for bus multiplexing or bus switching applications. Drive EN A/B low to place channels 1B through 4B in active mode, while channels 1A through 4A are in three-state mode. Drive EN A/B to logic-high (VL) to enable channels 1A through 4A, while channels 1B through 4B remain in three-state mode.

±15kV ESD Protection

As with all Maxim devices, ESD-protection structures are incorporated on all pins to protect against electrostatic discharges encountered during handling and assembly. The I/O V_{CC} lines have extra protection against static discharge. Maxim's engineers have developed state-of-the-art structures to protect these pins against ESD of ±15kV without damage. The ESD structures withstand high ESD in all states: normal operation, three-state output mode, and powered down. After an ESD event, Maxim's E versions keep working without latchup, whereas competing products can latch and must be powered down to remove latchup.

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

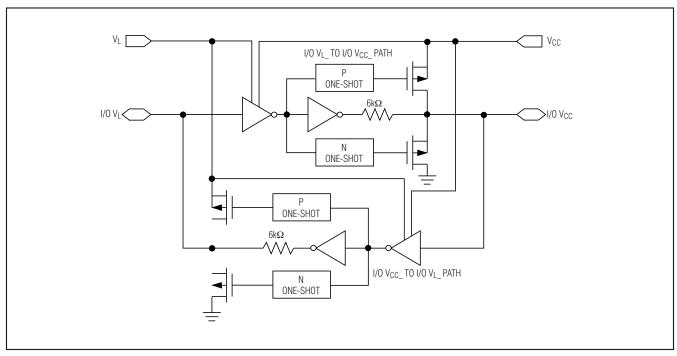


Figure 5. MAX3001E/MAX3002–MAX3012 Simplified Functional Diagram (1 I/O Line)

ESD protection can be tested in various ways. The I/O V_{CC} lines of the MAX3000E/MAX3001E are characterized for protection to $\pm 15 \, \text{kV}$ using the Human Body Model.

ESD Test Conditions

ESD performance depends on a variety of conditions. Contact Maxim for a reliability report that documents test setup, test methodology, and test results.

Human Body Model

Figure 7a shows the Human Body Model and Figure 7b shows the current waveform it generates when discharged into a low impedance. This model consists of a 100pF capacitor charged to the ESD voltage of interest, which is then discharged into the test device through a $1.5 \mathrm{k}\Omega$ resistor.

Machine Model

The Machine Model for ESD tests all pins using a 200pF storage capacitor and zero discharge resistance. Its objective is to emulate the stress caused by contact that occurs with handling and assembly during manufacturing. Of course, all pins require this protection during manufacturing, not just inputs and outputs. Therefore, after PCB assembly, the Machine Model is less relevant to I/O ports.

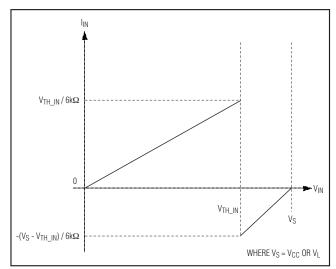


Figure 6. Typical I_{IN} vs. V_{IN}

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Applications Information

Power-Supply Decoupling

To reduce ripple and the chance of transmitting incorrect data, bypass V_L and V_{CC} to ground with a 0.1µF capacitor. To ensure full ± 15 kV ESD protection, bypass V_{CC} to ground with a 1µF capacitor. Place all capacitors as close to the power-supply inputs as possible.

I²C Level Translation

For I²C level translation for I²C applications, please refer to the MAX3372E–MAX3379E/MAX3390E–MAX3393E datasheet.

Unidirectional vs. Bidirectional Level Translator

The MAX3000E/MAX3001E/MAX3002/MAX3003 bidirectional translators can operate as a unidirectional device to translate signals without inversion. The MAX3004–MAX3012 unidirectional level translators, level-shift data in one direction ($V_L \rightarrow V_{CC}$ or $V_{CC} \rightarrow V_L$) on any single data line (see the *Ordering Information*.) These devices provide the smallest solution (UCSP package) for unidirectional level translation without inversion.

+1.2V to +5.5V, $\pm15kV$ ESD-Protected, $0.1\mu A$, 35Mbps, 8-Channel Level Translators

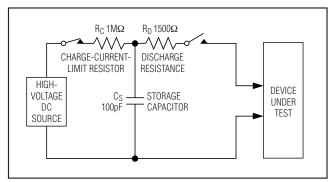


Figure 7a. Human Body ESD Test Model

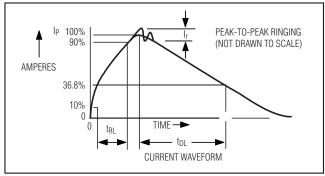


Figure 7b. Human Body Current Waveform

Selector Guide

PART	EN	EN A/B	Tx/Rx*	DATA RATE	ESD PROTECTION (kV)
MAX3000E	√	_	8/8	230kbps	±15
MAX3001E	√	_	8/8	4Mbps	±15
MAX3002	\checkmark	_	8/8	**	±2
MAX3003	_	√	8/8	**	±2
MAX3004	\checkmark	_	8/0	**	±2
MAX3005	\checkmark	_	7/1	**	±2
MAX3006	\checkmark	_	6/2	**	±2
MAX3007	$\sqrt{}$	_	5/3	**	±2
MAX3008	\checkmark	_	4/4	**	±2
MAX3009	$\sqrt{}$	_	3/5	**	±2
MAX3010	√	_	2/6	**	±2
MAX3011	√	_	1/7	**	±2
MAX3012	√	_	0/8	**	±2

 $^{^*}Tx = V_L \rightarrow V_{CC}; Rx = V_{CC} \rightarrow V_L$

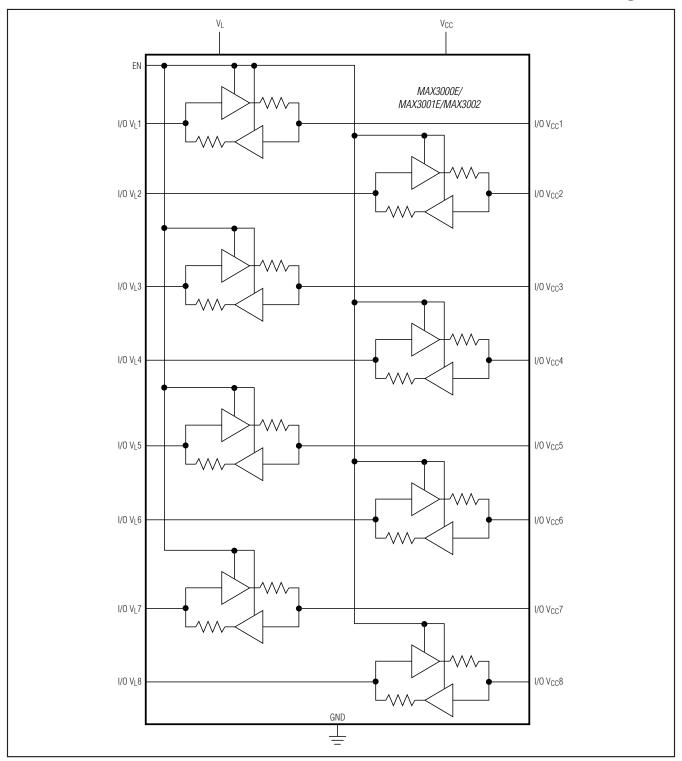
Table 1. Data Rate

V _L ↔ V _{CC} (V)	MAX3002-MAX3012 GUARANTEED DATA RATE (Mbps)
1.2 ↔ 5.5	40
1.2 ↔ 3.3	20
2.5 ↔ 3.3	35
1.8 ↔ 2.5	30
1.2 ↔ 2.5	20
1.2 ↔ 1.8	20

^{**}See Table 1.

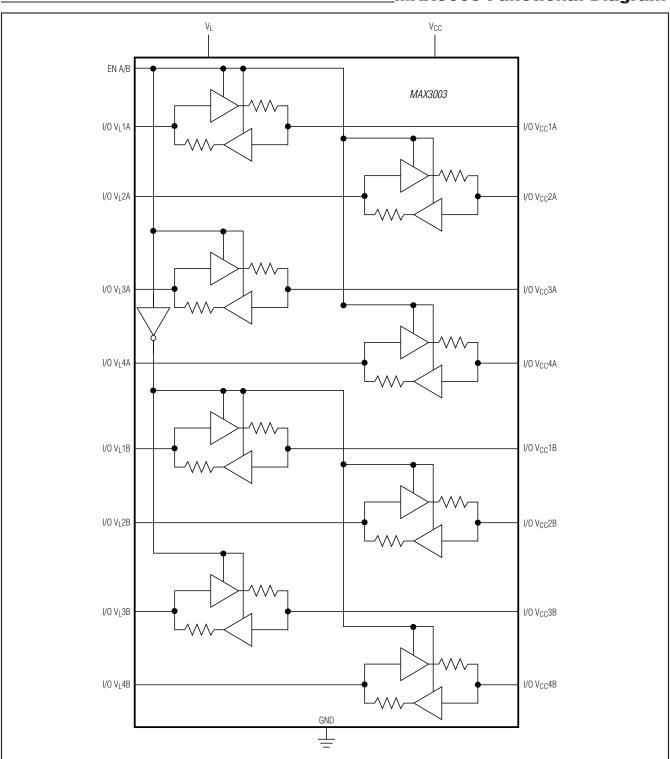
+1.2V to +5.5V, ±15kV ESD-Protected, 0.1µA, 35Mbps, 8-Channel Level Translators

MAX3000E/MAX3001E/MAX3002 Functional Diagram



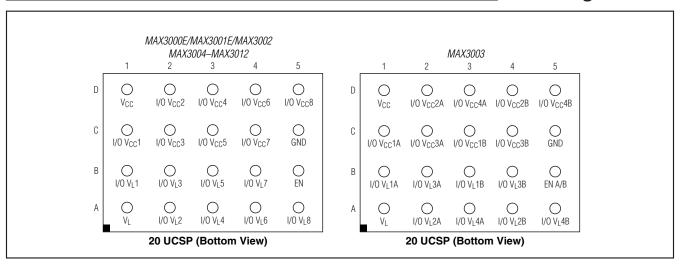
+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

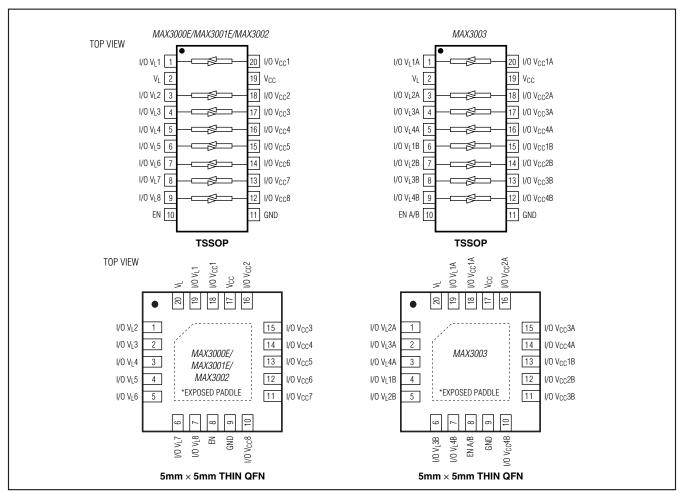
MAX3003 Functional Diagram



+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

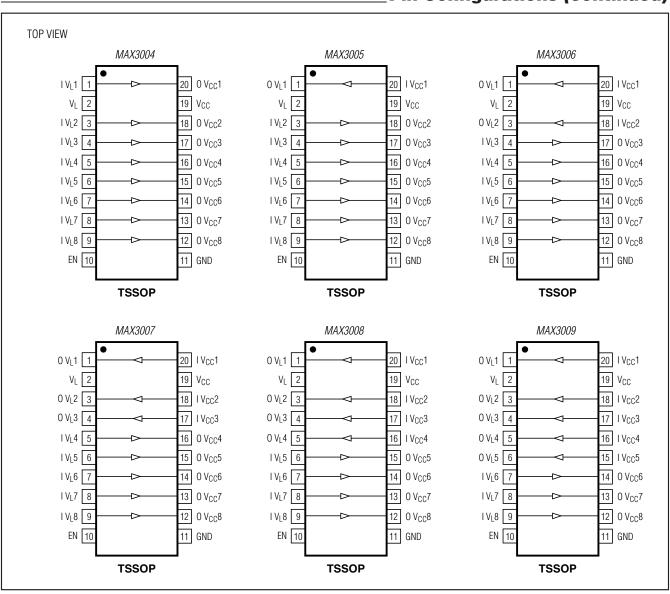
Pin Configurations





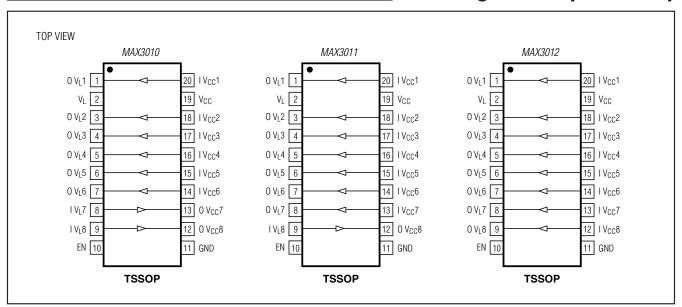
+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Pin Configurations (continued)



+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Pin Configurations (continued)



Ordering Information (continued)

PART	TEMP RANGE	PIN-PACKAGE	
MAX3001EEUP	-40°C to +85°C	20 TSSOP	
MAX3001EEBP-T*	-40°C to +85°C	4 x 5 UCSP	
MAX3001EETP	-40°C to +85°C	20 TQFN	
MAX3001EAUP	-40°C to +125°C	20 TSSOP	
MAX3002EUP	-40°C to +85°C	20 TSSOP	
MAX3002EBP-T*	-40°C to +85°C	4 x 5 UCSP	
MAX3002ETP	-40°C to +85°C	20 TQFN	
MAX3003EUP	-40°C to +85°C	20 TSSOP	
MAX3003EBP-T*	-40°C to +85°C	4 x 5 UCSP	
MAX3003ETP	-40°C to +85°C	20 TQFN	
MAX3004EUP	-40°C to +85°C	20 TSSOP	
MAX3004EBP-T*	-40°C to +85°C	4 x 5 UCSP	
MAX3005EUP	-40°C to +85°C	20 TSSOP	
MAX3005EBP-T*	-40°C to +85°C	4 x 5 UCSP	
MAX3006EUP	-40°C to +85°C	20 TSSOP	
MAX3006EBP-T*	-40°C to +85°C	4 x 5 UCSP	

PART	TEMP RANGE	PIN-PACKAGE	
MAX3007EUP	-40°C to +85°C	20 TSSOP	
MAX3007EBP-T*	-40°C to +85°C	4 x 5 UCSP	
MAX3008EUP	-40°C to +85°C	20 TSSOP	
MAX3008EBP-T*	-40°C to +85°C	4 x 5 UCSP	
MAX3009EUP	-40°C to +85°C	20 TSSOP	
MAX3009EBP-T*	-40°C to +85°C	4 x 5 UCSP	
MAX3010EUP	-40°C to +85°C	20 TSSOP	
MAX3010EBP-T*	-40°C to +85°C	4 x 5 UCSP	
MAX3011EUP	-40°C to +85°C	20 TSSOP	
MAX3011EBP-T*	-40°C to +85°C	4 x 5 UCSP	
MAX3012EUP	-40°C to +85°C	20 TSSOP	
MAX3012EBP-T*	-40°C to +85°C	4 x 5 UCSP	

^{*}Future product—contact factory for availability.

_Chip Information

TRANSISTOR COUNT: 1184

PROCESS: BICMOS

⁻T = Tape-and-reel package.

+1.2V to +5.5V, $\pm15kV$ ESD-Protected, $0.1\mu A$, 35Mbps, 8-Channel Level Translators

Package Information

For the latest package outline information and land patterns, go to www.maxim-ic.com/packages

PACKAGE TYPE	PACKAGE CODE	DOCUMENT NO.
20 TSSOP	U20-3	<u>21-0066</u>
20 TQFN	T2055-4	<u>21-0140</u>
4 x 5 UCSP	B20-1	<u>21-0095</u>

+1.2V to +5.5V, ±15kV ESD-Protected, 0.1μA, 35Mbps, 8-Channel Level Translators

Revision History

REVISION NUMBER	REVISION DATE	DESCRIPTION	PAGES CHANGED
4	12/06	Added TQFN packages	1, 2, 3, 10, 11, 15, 16, 21, 23–26
5	8/08	Changed pin description and package drawing	1, 10, 11, 23



Maxim cannot assume responsibility for use of any circuitry other than circuitry entirely embodied in a Maxim product. No circuit patent licenses are implied. Maxim reserves the right to change the circuitry and specifications without notice at any time. The parametric values (min and max limits) shown in the Electrical Characteristics table are guaranteed. Other parametric values quoted in this data sheet are provided for guidance.

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25